


<b>Search Notes</b>  	<b>Application/Control No.</b>  10075051	<b>Applicant(s)/Patent Under Reexamination</b>  WANG ET AL.
	<b>Examiner</b>  DJENANE M BAYARD	<b>Art Unit</b>  2444

SEARCHED			
Class	Subclass	Date	Examiner
709	217, 218, 219, 226, 229	6/01/09	db

SEARCH NOTES		
Search Notes	Date	Examiner
East	6/01/09	db
Double Patenting	6/01/09	db

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
709	217, 218, 219, 226, 229	6/01/09	db

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